Search Notes

Application/Control No.	Applicant(s)/Patent un Reexamination	nder
10/052,268	KOBAYASHI, NAOFUMI	
Examiner	Art Unit	
Andrew Lee	2616	

	SEARCHED				
Class	Subclass	Date	Examiner		
370	338, 252	4/11/2006	AL		
		-			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	<u></u>				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Updated DiV search area from U.S. Patent Number 6,359,873	4/11/2006	AL